

<b>Notice of References Cited</b>	Application/Control No. 09/776,166	Applicant(s)/Patent Under Reexamination REED ET AL.	
	Examiner Tamai IE Karl	Art Unit 2834	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,969,848	10-1999	Lee et al.	359/298
*	B	US-5,908,986	06-1999	Mitamura, Takeshi	73/504.12
*	C	US-5,995,334	11-1999	Fan et al.	360/294.3
*	D	US-6,091,537	07-2000	Sun et al.	359/248
*	E	US-6,415,068	07-2002	Sun, Decai	385/16
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Baidya et al., "MEMS Component Extraction", 4/1999, Technical Proceedings of the 1999 International Conference on Modeling and Simulation of Microsystems.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.